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Afzali-Ardakani et al.

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(54) **DNA SEQUENCING USING A SUSPENDED CARBON NANOTUBE**

IPC G01N 27/447, 27/02, 33/487; H01L 21/44; B82Y 30/00, 15/00; C12Q 1/686
See application file for complete search history.

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 476 days.

This patent is subject to a terminal disclaimer.

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(57) **ABSTRACT**

A technique is provided for forming a nanodevice for sequencing. A bottom metal contact is disposed at a location in an insulator that is on a substrate. A nonconducting material is disposed on top of the bottom metal contact and the insulator. A carbon nanotube is disposed on top of the nonconducting material. Top metal contacts are disposed on top of the carbon nanotube at the location of the bottom metal contact, where the top metal contacts are formed at opposing ends of the carbon nanotube at the location. The carbon nanotube is suspended over the bottom metal contact at the location, by etching away the nonconducting material under the carbon nanotube to expose the bottom metal contact as a bottom of a trench, while leaving the nonconducting material immediately under the top metal contacts as walls of the trench.

7 Claims, 11 Drawing Sheets

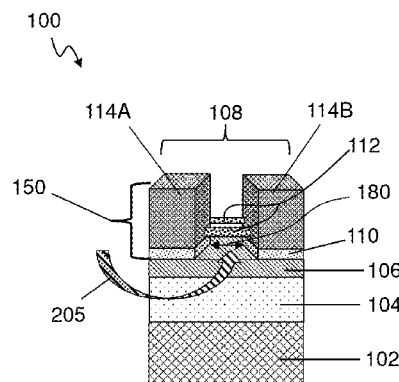
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C12Q 1/68 (2006.01)
G01N 27/447 (2006.01)
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(52) **U.S. Cl.**
CPC **C12Q 1/6869** (2013.01); **G01N 27/44791** (2013.01); **G01N 33/48721** (2013.01)

(58) **Field of Classification Search**
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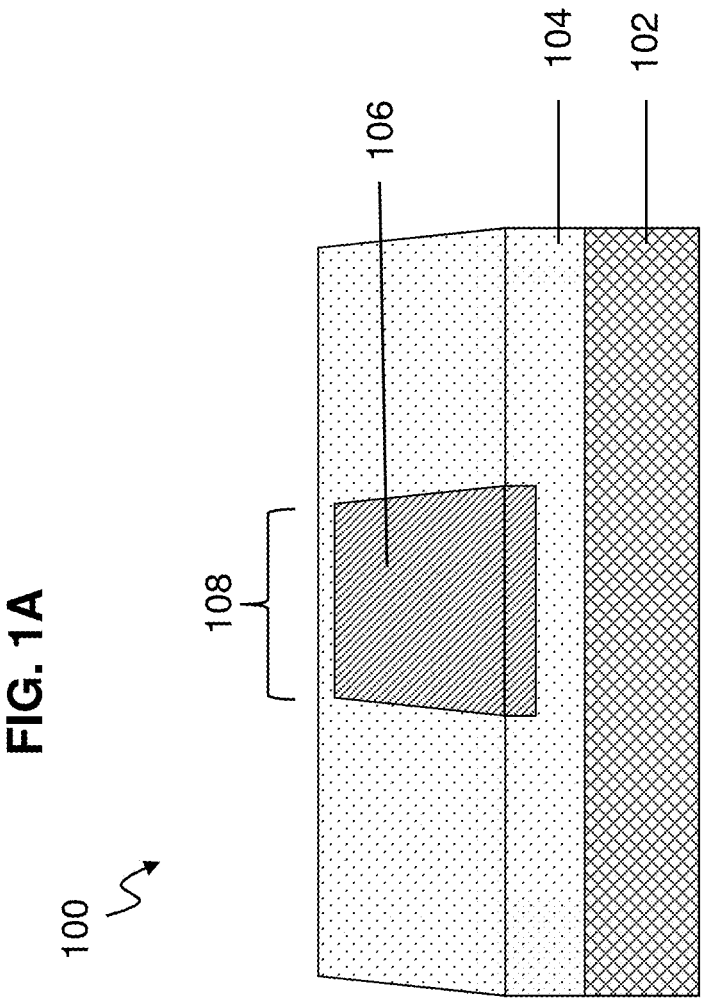


FIG. 1B

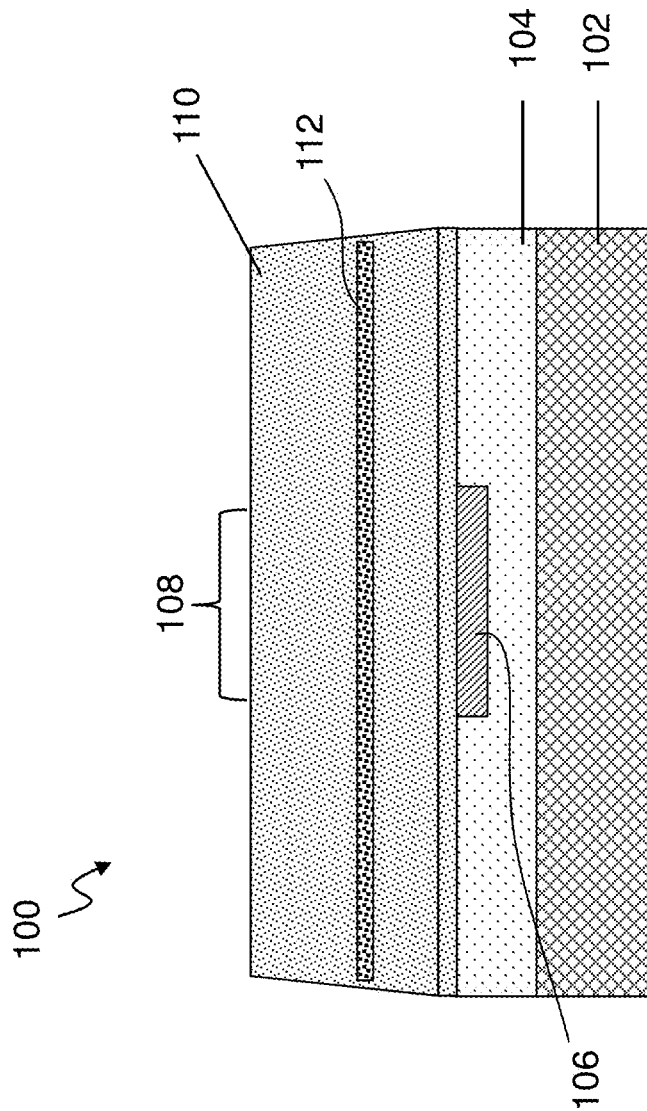


FIG. 1C

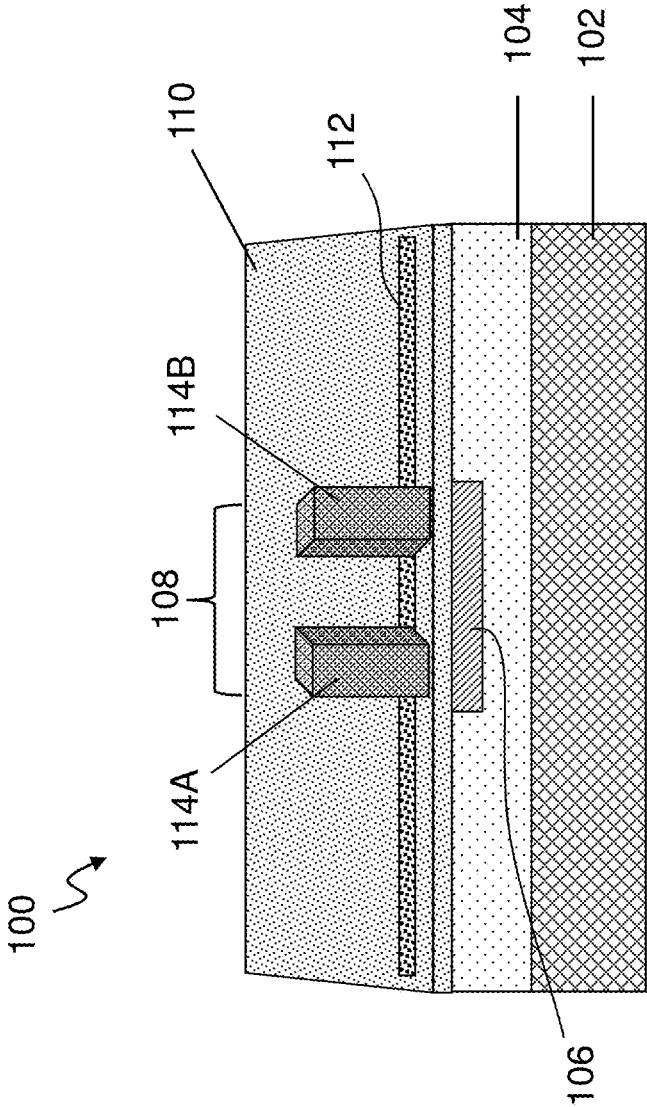


FIG. 1D

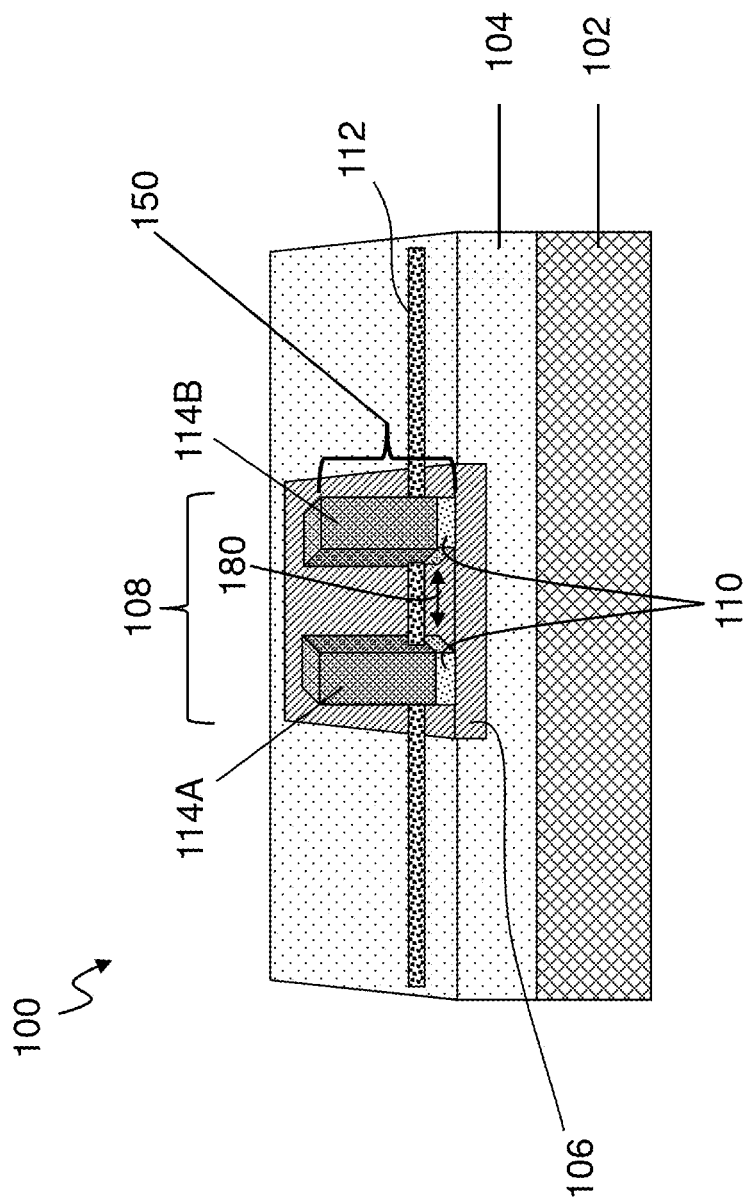


FIG. 2

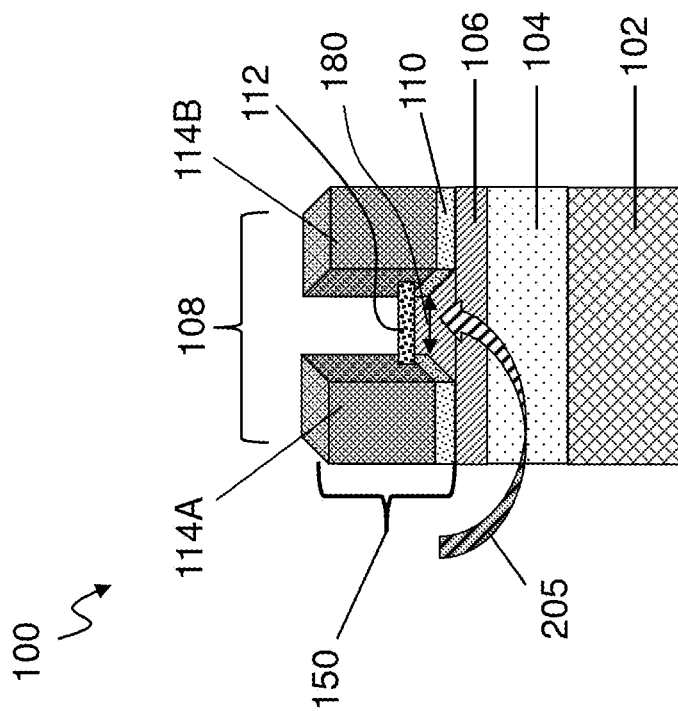
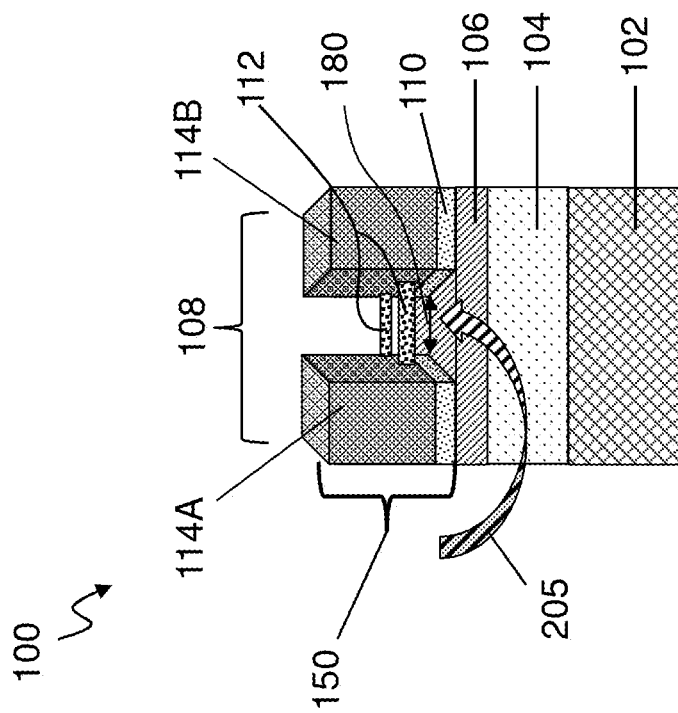


FIG. 3



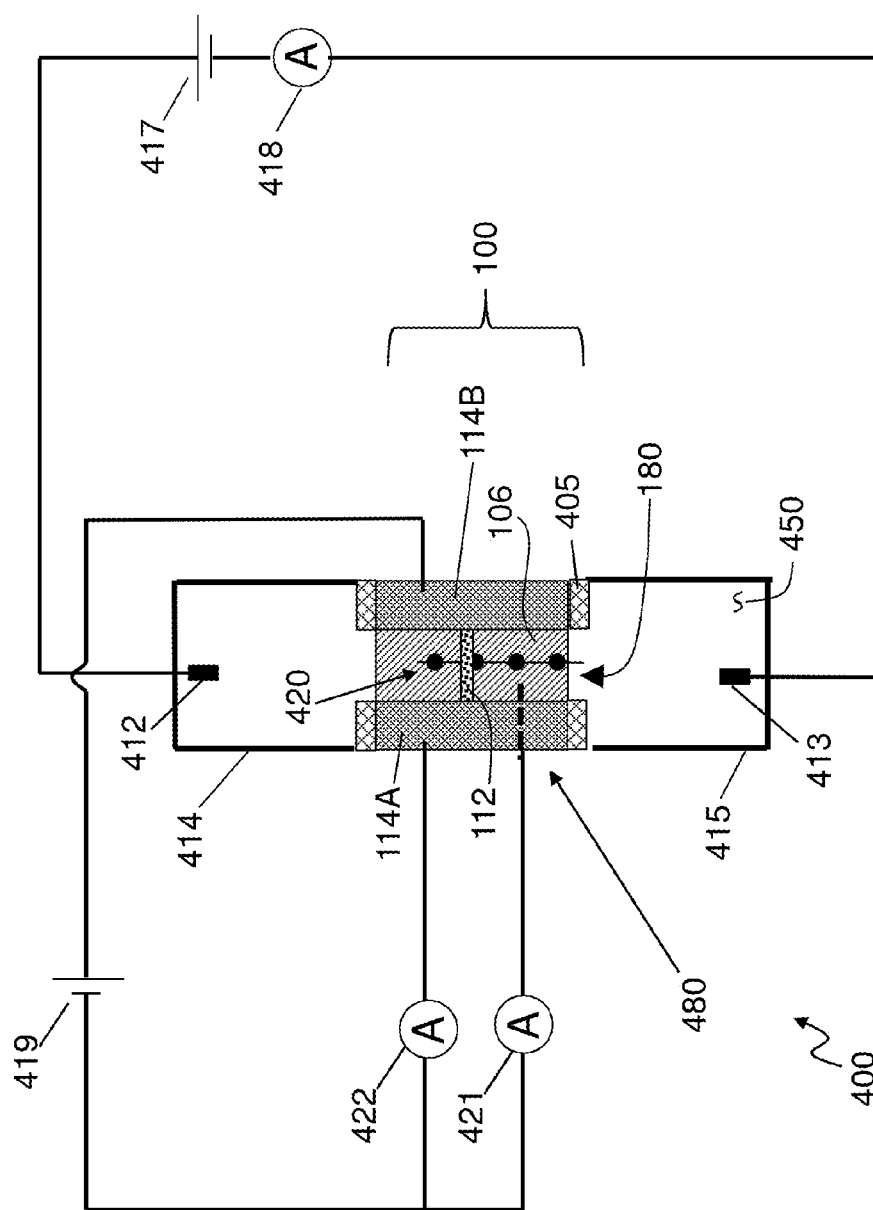


FIG. 4

FIG. 5

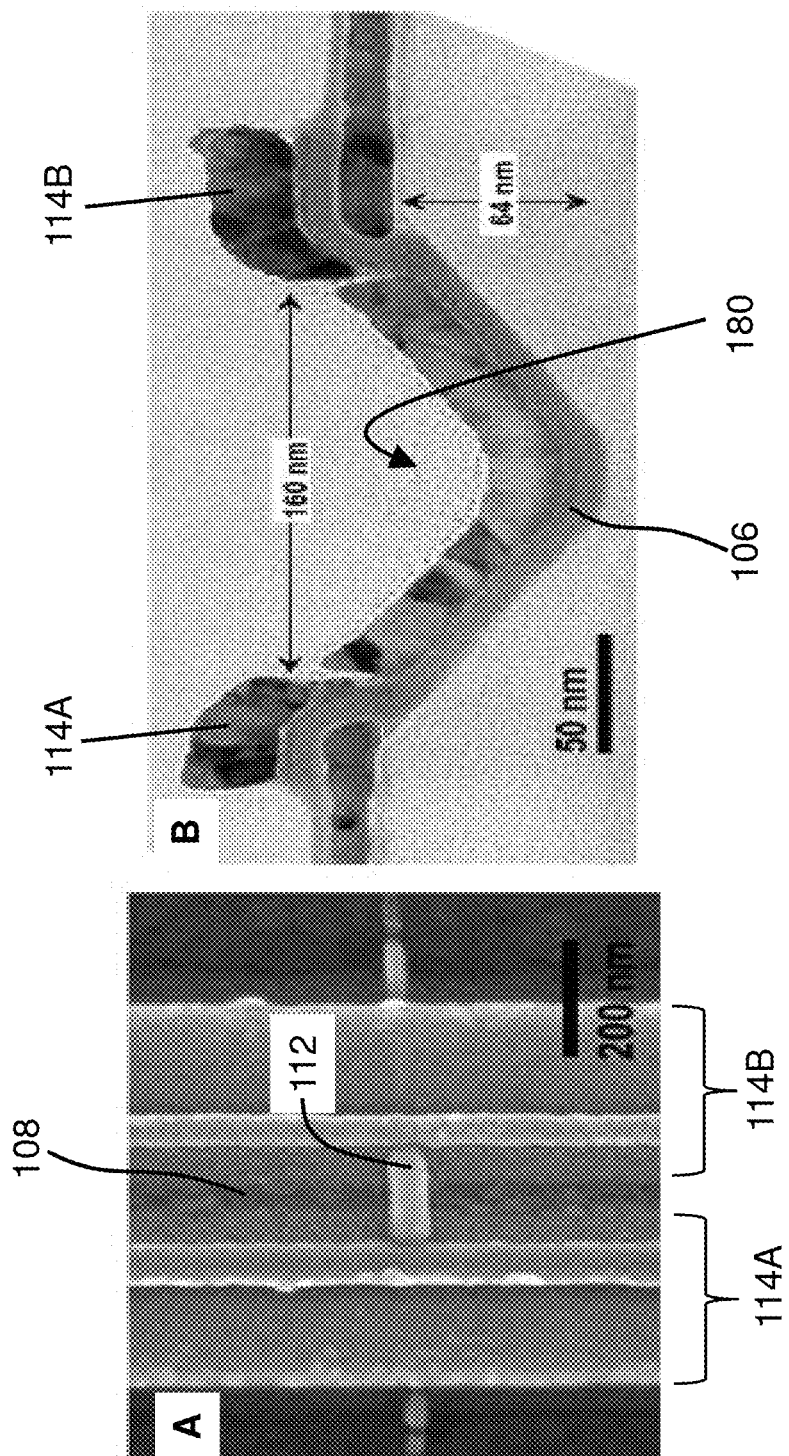


FIG. 6

600

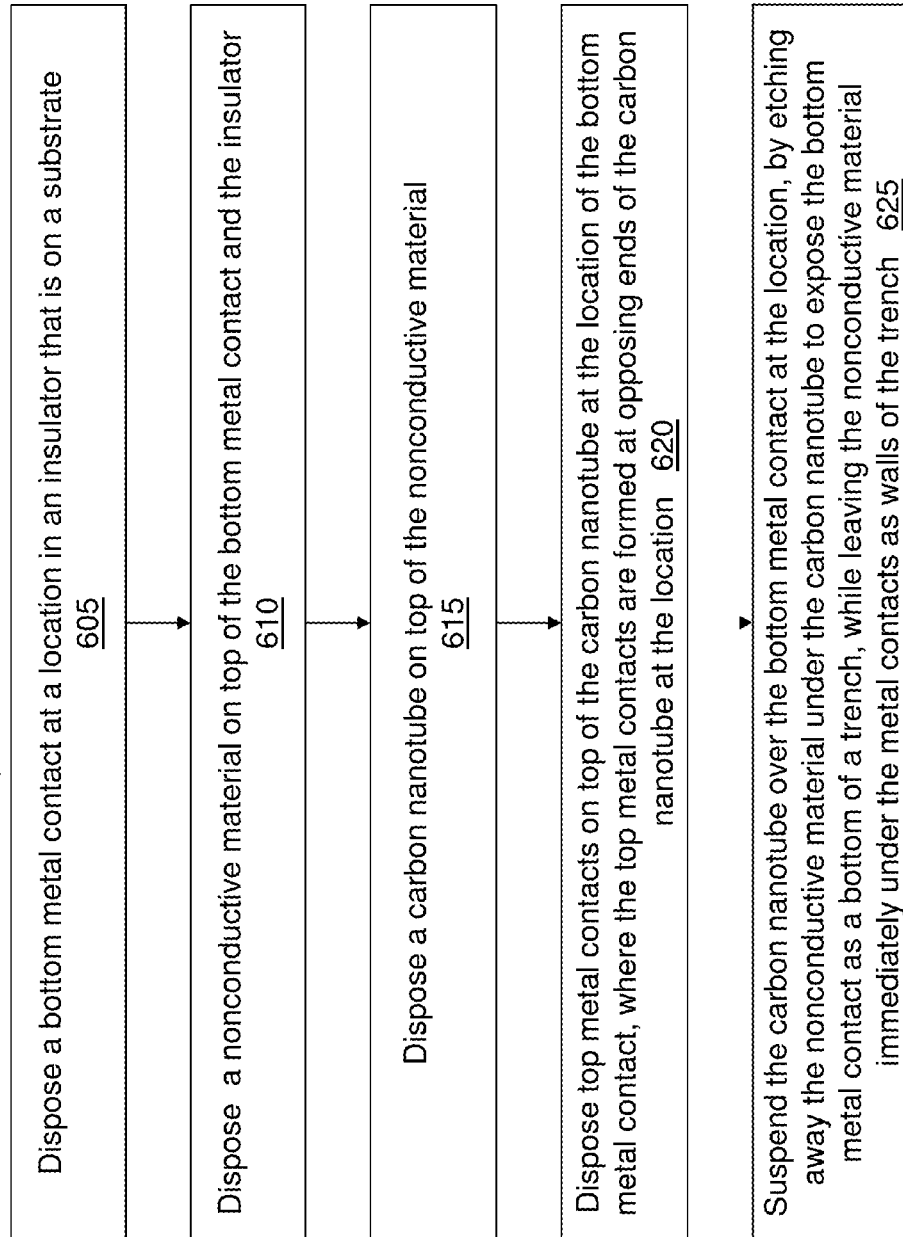


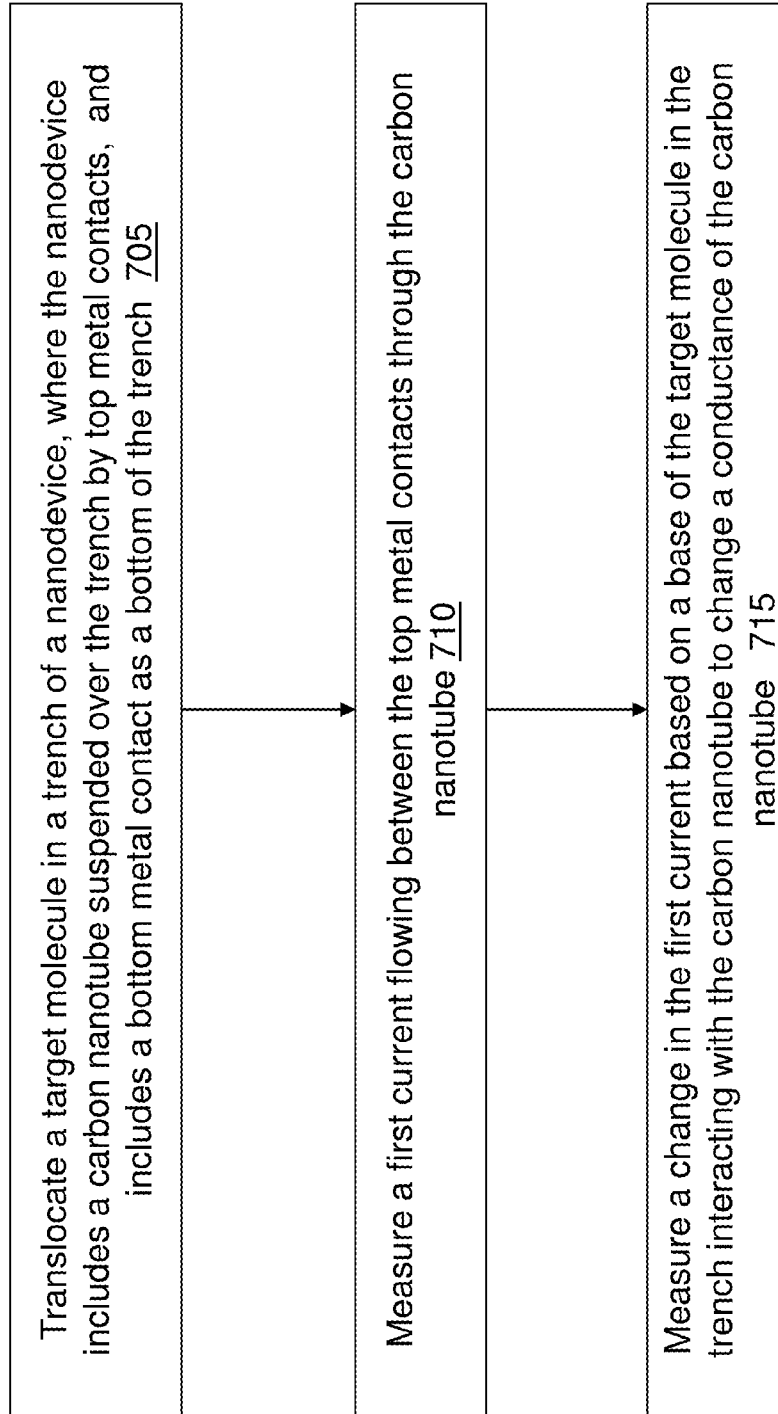
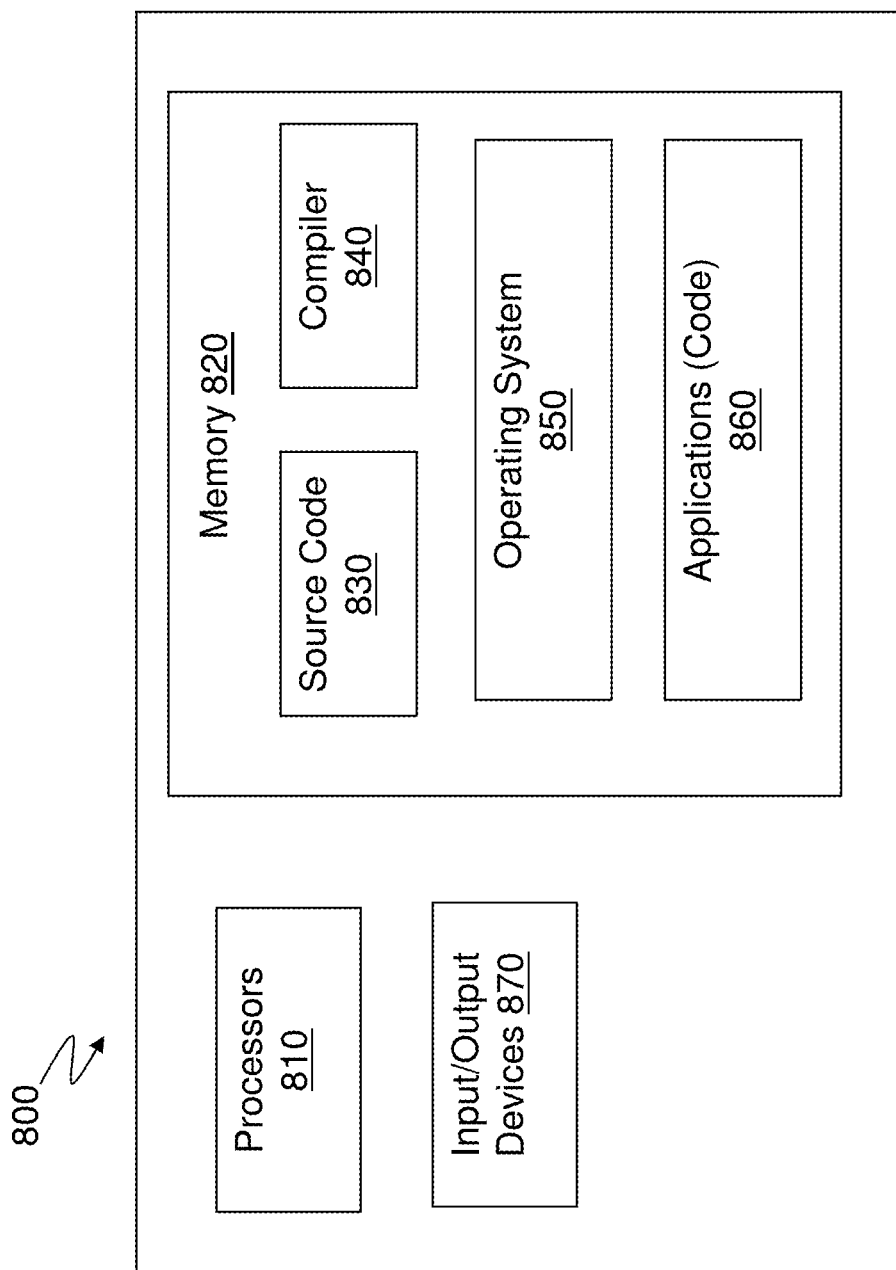
FIG. 7700 

FIG. 8



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DNA SEQUENCING USING A SUSPENDED CARBON NANOTUBE

CROSS REFERENCE TO RELATED APPLICATIONS

The present application is a continuation of U.S. patent application Ser. No. 14/014,791, entitled "DNA SEQUENCING USING A SUSPENDED CARBON NANOTUBE", filed on Aug. 30, 2013, which is incorporated herein by reference in its entirety.

BACKGROUND

The present invention relates generally to nanodevices, and more specifically, to a nanodevice with one or more suspended carbon nanotubes for sequencing.

Nanopore sequencing is a method for determining the order in which nucleotides occur on a strand of deoxyribonucleic acid (DNA). A nanopore (also referred to as pore, nanochannel, hole, etc.) can be a small hole in the order of several nanometers in internal diameter. The theory behind nanopore sequencing is about what occurs when the nanopore is submerged in a conducting fluid and an electric potential (voltage) is applied across the nanopore. Under these conditions, a slight electric current due to conduction of ions through the nanopore can be measured, and the amount of current is very sensitive to the size and shape of the nanopore. If single bases or strands of DNA pass (or part of the DNA molecule passes) through the nanopore, this can create a change in the magnitude of the current through the nanopore. Other electrical or optical sensors can also be positioned around the nanopore so that DNA bases can be differentiated while the DNA passes through the nanopore.

The DNA can be driven through the nanopore by using various methods, so that the DNA might eventually pass through the nanopore. The scale of the nanopore can have the effect that the DNA may be forced through the hole as a long string, one base at a time, like thread through the eye of a needle. Recently, there has been growing interest in applying nanopores as sensors for rapid analysis of biomolecules such as deoxyribonucleic acid (DNA), ribonucleic acid (RNA), protein, etc. Special emphasis has been given to applications of nanopores for DNA sequencing, as this technology holds the promise to reduce the cost of sequencing below \$1000/human genome.

SUMMARY

According to one embodiment, a method of forming a nanodevice for sequencing is provided. The method includes disposing a bottom metal contact at a location in an insulator that is on a substrate, disposing a nonconducting material on top of the bottom metal contact and the insulator, and disposing a carbon nanotube on top of the nonconducting material. The method includes disposing top metal contacts on top of the carbon nanotube at the location of the bottom metal contact, in which the top metal contacts are formed at opposing ends of the carbon nanotube at the location. The method includes suspending the carbon nanotube over the bottom metal contact at the location, by etching away the nonconducting material under the carbon nanotube to expose the bottom metal contact as a bottom of a trench, while leaving the nonconducting material immediately under the top metal contacts as walls of the trench.

According to one embodiment, a method of sequencing is provided. The method includes translocating a target mol-

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ecule in a trench on a substrate of a nanodevice, where the nanodevice includes a carbon nanotube suspended over the trench by top metal contacts, and includes a bottom metal contact as a bottom of the trench. A buffer solution is passed both below and above the carbon nanotube, where the carbon nanotube is functionalized with an organic compound having two different functional groups on either end in which one functional group attaches to the carbon nanotube and another functional group interacts with the target molecule. The method includes measuring a first current flowing between the top metal contacts through the carbon nanotube, and measuring a change in the first current based on a base of the target molecule in the trench interacting with the carbon nanotube to change a conductance of the carbon nanotube.

According to one embodiment, a device for sequencing is provided. The device includes a bottom metal contact formed at a location in an insulator that is on a substrate, a nonconducting material disposed on top of the bottom metal contact and the insulator, and a carbon nanotube disposed on top of the nonconducting material. The top metal contacts are disposed on top of the carbon nanotube at the location of the bottom metal contact, where the top metal contacts are formed at opposing ends of the carbon nanotube at the location. The carbon nanotube is suspended over the bottom metal contact at the location, based on etching away the nonconducting material under the carbon nanotube to expose the bottom metal contact as a bottom of a trench, while leaving the nonconducting material immediately under the top metal contacts as walls of the trench.

Additional features and advantages are realized through the techniques of the present invention. Other embodiments and aspects of the invention are described in detail herein and are considered a part of the claimed invention. For a better understanding of the invention with the advantages and the features, refer to the description and to the drawings.

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE DRAWINGS

The subject matter which is regarded as the invention is particularly pointed out and distinctly claimed in the claims at the conclusion of the specification. The forgoing and other features, and advantages of the invention are apparent from the following detailed description taken in conjunction with the accompanying drawings in which:

FIGS. 1A through 1D illustrate perspective views of a method of forming a device with a trench according to an embodiment, in which:

FIG. 1A illustrates an electrically insulating substrate with an embedded bottom metal contact;

FIG. 1B illustrates depositing a nonconducting material and carbon nanotube on the device;

FIG. 1C illustrates depositing two top metal contacts on the device; and

FIG. 1D illustrates suspending the carbon nanotube over the bottom metal contact and the trench.

FIG. 2 illustrates a perspective view of the (final) device with the suspended carbon nanotube according to an embodiment.

FIG. 3 illustrates a perspective view of the device with multiple carbon nanotubes according to an embodiment.

FIG. 4 illustrates a schematic of a system for sequencing using the device according to an embodiment.

FIG. 5 illustrates a transmission electron microscope (TEM) of the device according to an embodiment.

FIG. 6 illustrates a method of forming the device for sequencing according to an embodiment.

FIG. 7 illustrates a method of sequencing with the device according to an embodiment.

FIG. 8 is a block diagram that illustrates an example of a computer (computer test setup) having capabilities, which may be included in and/or combined with embodiments.

DETAILED DESCRIPTION

One of the recognized hurdles in the scientific world is to engineer a device that can efficiently and effectively sequence DNA. To sequence DNA means to determine the order of nucleotides in anything from individual genes to entire genomes. While many devices and techniques have been developed over the years, there is still recognition for more rapid throughput and greater precision in sequencing. One approach of intense study is that of nanopore sequencing, where a strand of DNA is immersed in an ionic medium and passed through a nanopore that contains a series of electrodes. When a nucleotide on the DNA obstructs the current between the nanopore electrodes it is detected, providing a unique disruption based upon the type of nucleotide. In the scientific world, the difficulty is in fabricating such nanopores at the needed dimensions in a cost-effective and reproducible manner.

Embodiments offer a solution to this difficulty by providing a structure or nanodevice (as a chip) that is able to sequence the DNA or RNA in a fashion similar to that of the nanopore sequencing using trenches in a substrate rather than small pores.

Embodiments include a device that can sequence DNA using a carbon nanotube (CNT) that is suspended over a narrow trench. In this technique, the idea is that a single CNT is contacted by (top) metal electrodes on either side of a trench and at the bottom of the trench is a second electrode. Immersing the chip in an ionic solution creates a current between the CNT and the bottom electrode. DNA passes through the trench, with each nucleotide of the strand disrupting the current between the bottom electrode and the CNT in a unique way, thus providing the sequence of the DNA. One advantage is that such a trench structure can be readily fabricated using a crystalline silicon substrate and common wet etching and does not require the challenging fabrication of nanopores. In addition to being submersed, an embodiment includes a device that has a reservoir built in that allows one to flow the solution from one reservoir, through the channel, and into another reservoir.

FIGS. 1A through 1D illustrate perspective views of a method of forming nanodevice 100 with a trench according to an embodiment.

FIG. 1A illustrates that the nanodevice 100 has an electrically insulating substrate 102 which may be a silicon wafer, a germanium wafer, and/or a combination of both. An oxide layer 104 may be deposited (e.g., grown) on top of the substrate 102. The oxide layer 104 acts as an insulator, and the oxide layer 104 be any material including silicon dioxide, germanium oxide, etc. As an example, the oxide layer 104 is greater than 100 nanometers (nm) thick (e.g., the oxide layer 104 may be 1 micrometer (μm) thick).

A bottom metal contact 106 is deposited on the oxide layer 104 in order to embed the bottom metal contact 106 in the oxide layer 104 at a location 108. The following is one example of embedding the bottom metal contact 106 in the oxide layer 104. A cavity is etched in the oxide layer 104 at location 108. The cavity may be etched using a mask (such as photolithography) and wet etchant, and/or etched using

transmission electron microscopy (TEM) (e.g., via an electron microscope). Next, a film of metal (i.e., to form the bottom metal electrode 106) is deposited in the cavity and on top of the oxide layer 104. Chemical mechanical polishing (CMP) is performed (on top of nanodevice 100) to remove the excess metal from the top of the oxide layer 104 and to planarize the bottom metal contact 106 (which smooths its top surface) within the cavity. This results in the bottom metal contact 106 being embedded in the oxide layer 104 as a smooth planar surface (e.g., the top surface of the bottom metal contact 106 is level with the top surface of the oxide layer 104).

FIG. 1B illustrates depositing or transferring a thin layer of nonconducting material 110 directly on top of both the embedded bottom metal contact 106 and the oxide layer 104. In one case, the thin layer of nonconducting material 110 is deposited or transferred to be only a few nanometers (nm) thick, such as 5 to 8 nm thick. In another case, a thicker nonconducting material 110 may be deposited/transferred initially, and then controllably etched down to a sub-10 nm thickness (e.g., 5 to 8 nm thick). The thickness of the nonconducting material 110 determines the depth of the trench (trench 180 discussed below).

Particularly, the deposited/transferred nonconducting material 110 may be silicon with a $\langle 110 \rangle$ crystal surface orientation. As discussed below, the $\langle 110 \rangle$ crystal surface orientation allows for a wet etchant (e.g., KOH) to be used to provide a cleanly vertical etch (i.e., anisotropic etch) to the thin silicon $\langle 110 \rangle$ without undercutting top metal contacts (discussed further below).

In FIG. 1B, a carbon nanotube 112 is placed/transferred on top of the nonconducting material 110 such that the carbon nanotube (CNT) 112 is positioned to horizontally extend across the embedded bottom metal contact 106 at the location 108.

FIG. 1C illustrates that two top metal contact 114A and 114B (generally referred to as top metal contacts 114) are deposited directly on top of both the carbon nanotube 112 and the nonconducting material 110 at the location 108. The top metal contacts 114 are both electrically and physically contact to the carbon nanotube 112. The top metal contacts 114 may be palladium (Pd), gold, silver, etc.

The top metal contact 114A is horizontally separated from (spaced apart) the top metal contact 114B by a distance of, for example, 20-100 nm (nanometer). The two top metal contacts 114 may be formed by standard lithographic processing. In one case, a patterned mask may be applied on top of the carbon nanotube 112 and the nonconducting material 110, and the metal (e.g., 1 to 5 μm thick) is deposited on the patterned mask. The patterned mask (along with the metal on top) is removed to leave the two top metal contacts 114A and 114B according to the pattern. In another case, the metal is deposited on top of the carbon nanotube 112 and the nonconducting material 110, and a patterned mask is deposited to protect the metal underneath, while the exposed metal is removed. When the patterned mask is removed, the two top metal contacts 114A and 114B remain according to the pattern.

FIG. 1D illustrates suspending the carbon nanotube 112 over the bottom metal contact 106 at the location 108, in which the two top metal contacts 114 each serve as a mask for creating the trench 180. For example, a wet etch, such as potassium hydroxide (KOH) or tetramethylammonium hydroxide (TMAH), may be utilized to anisotropically etch away the nonconducting material 110 (e.g., silicon $\langle 110 \rangle$) except from under the two top metal contacts 114. The nonconducting material 110 underneath the two top metal

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contacts **114** is masked from the wet etchant. Because of the anisotropic etching of the nonconducting material **110** (e.g., silicon with <110> crystalline surface orientation) to leave the thin layer of nonconducting material **110** underneath the each respective top metal contact **114A** and **114B**, the anisotropic etching results in two vertical pillars **150** which comprise the top metal contacts **114** and the nonconducting material **110** underneath. Under the now suspended carbon nanotube **112**, a trench **180** is formed between the remaining nonconducting material **110** of the vertical pillars **150**. As can be seen, the walls of the trench **180** are formed of nonconducting material **110** of the vertical pillars **150** while the bottom of the trench **180** is the exposed bottom metal contact **106**. As one example, the height of the walls (i.e., depth) of the trench may be 5 nm.

According to an embodiment, FIG. 2 illustrates a perspective view of the (final) nanodevice **100** with the suspended carbon nanotube **112** (in direct electrical and physical contact with the top metal contacts **114**) as one electrode and the embedded bottom metal contact **106**. The structure of the nanodevice **100** has the trench **180** that has a length determined by the length of the top metal contacts **114A** and **114B**. The length of the top metal contacts **114** may be, for example, 100-1000 nm. The distance separating the two top metal contacts **114A** and **114B** determines the width of the trench **180**. The width of the trench may be, for example, 20-100 nm.

In FIG. 2, an arrow **205** shows the trench **180** through which a DNA molecule passes, disrupting the ionic current between the suspended carbon nanotube **112** (above) and the underlying embedded bottom metal contact **112**.

FIG. 3 illustrates a perspective view of the nanodevice **100** with multiple carbon nanotubes according to an embodiment. Note that multiple bottom metal contacts **106** may be separately embedded (in a column but not touching) and each embedded metal contact **106** has its own carbon nanotube **112** positioned across, as discussed above.

In FIG. 3, the arrow **205** represents that DNA molecule travels underneath both of the carbon nanotubes **112**, and the thus the ionic current can be separately measured by the two carbon nanotubes **112**.

FIG. 4 illustrates a schematic of a system **400** for sequencing using the nanodevice **100** according to an embodiment. As discussed above, the nanodevice **100** includes the electrically insulating substrate **102** (wafer), the oxide layer **104**, the embedded bottom metal contact **106**, the nonconducting material **110** underneath the two top metal contacts **114A** and **114B** (which form the vertical pillars **150**), and the suspended carbon nanotube **112**. Dashed lines illustrate a connection **480** underneath (the device **100**) to the bottom metal contact **106**. The bottom metal contact **106** is connected to the negative polarity of voltage source **419** through an ammeter **421**.

In the system **400**, two reservoirs **414** and **415** are attached to opposite sides of the trench **180**. Each reservoir **414** and **415** is attached and sealed to respective ends of the nanodevice **100**, such that buffer solution **450** can flow in the trench **180** and in the reservoirs **414** and **415**. Sealing material **405** (which may include O-rings, epoxy, etc.) is utilized to seal the two reservoirs **414** and **415** to opposite ends of the trench **180** (nanodevice **100**). One skilled in the art understands how to seal the ends of the nanodevice **100** to respective reservoirs **414** and **415** using standard techniques in the art. The buffer solution **450** may be a salt solution (e.g., such as NaCl) capable of conducting electricity. The buffer solution **450** only flows in the trench **180** and only contacts the bottom metal contact **106** and the side

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walls of nonconducting material **110** (underneath the top metal contacts **114A** and **114B**). However, the buffer solution **450** does not contact the top metal contacts **114A** nor the carbon nanotube **112**, and only contacts the bottom metal contact **106**.

Electrode **412** is in one reservoir **414**, and electrode **413** is in the other reservoir **415**. The electrodes **412** and **413** are connected to a voltage source **417** for driving a target molecule **420** into the trench **180**. Electrodes **412** and **413** may be silver/silver chloride, or platinum for example. The reservoirs **415** and **414** are the inlet and outlet, respectively, for the buffer solution **450**, and reservoirs **414** and **415** hold the DNA, RNA, and/or protein samples for sequencing.

Note that the carbon nanotube **112** is a functionalized carbon nanotube **112** that has been coated with an organic coating. The organic compound can be covalently attached to the carbon nanotube **112** or non-covalently attached (i.e. via pi-pi interactions). The organic coating can be any organic coating that has/forms a transient bond, such as a hydrogen bond, with individual DNA bases (or RNA bases). By the transient bond, the negatively charged DNA molecule **420** will be trapped inside the trench **180** against thermal agitation/motion of the buffer solution **450**. The transient bond means that a single DNA base is attached to the functionalized carbon nanotube **112**. With a predefined voltage applied by the voltage source **417**, the transient bonds can be broken and the negatively charged DNA molecule can be driven through the trench **180** via the electrical field produced by the voltage source **417**. Examples of organic coatings include compounds that can perform hydrogen bond with nucleotides, such as, e.g., carboxylic acids, phosphonic acids, amides and cyclic bases like imidazole or benzimidazoles. These functionalities can be introduced as covalently functionalized moieties via reaction of functionalized diazonium salts or via pi-pi interactions of functionalized condensed aromatic compounds like pyrenebutyric acids.

In the system **400**, the target molecule **420** is the molecule being analyzed and/or sequenced. As an example DNA sample, the system **400** may include a single stranded DNA molecule **420** that is passing through the trench **180**. The DNA molecule **420** has bases (A, G, C, and T) represented as solid ovals.

The DNA molecule **420** is pulled through the trench **180** by a longitudinal electrical field generated by the voltage source **417**. When voltage is applied to electrodes **412** and **413** by the voltage source **417**, the voltage generates the electric field (between reservoirs **414** and **415**) that controllably (e.g., by turning on and off the voltage source **417**) drives the DNA molecule **420** into and through the trench **180**. Ammeter **418** monitors the ionic current change when DNA (or RNA) molecule **420** goes through trench **180**. The ionic current (measured by the ammeter **418**) flows through electrode **412**, into the buffer solution **450**, through the trench **180** (to interact with the target molecule **420** when present in the trench **180**), out through the electrode **413**.

A voltage source **419** is connected to top metal contact **114B** and top metal contact **114A** through the functionalized carbon nanotube **112**, and the current is measured by ammeter **422**. The ammeter **422** measures a change in current, which results from a change in conductance for the carbon nanotube **112**. Note that conductance is inversely related to resistance. When no base of the DNA molecule **420** is attached (e.g., via the transient bond (such as a hydrogen bond)) to the carbon nanotube **112**, the ammeter **422** measures a baseline current corresponding to no change in conductance (i.e., no change in resistivity) in the carbon

nanotube 112. However, when the negatively charged DNA molecule 420 is in the trench 180 and when a DNA base attaches to (e.g., forms a transient bond to) the functionalized carbon nanotube 112, the conductance changes (i.e., increases) in the carbon nanotube 112 which causes the current measured by the ammeter 422 to change (i.e., increase). When respectively attached to the carbon nanotube 112, each negatively charged individual DNA (or RNA) base of the target molecule 420 causes the conductance to increase a predefined amount by providing detectable charge to the carbon nanotube 112. As a result of the increase in charge to the carbon nanotube 112, this increase in conductance causes a measured increase in current measured by the ammeter 422 to uniquely identify the attached DNA base. Each DNA base of the DNA molecule 420 causes a predefined change/increase in current that uniquely identifies the respective bases that consecutively pass underneath and attach to the carbon nanotube 112. Accordingly, the target molecule 420 is sequenced.

When the DNA base is attached to the carbon nanotube 112, the current flows into top metal contact 114B, into the carbon nanotube 112 (in which the attached DNA base interacts with the carbon nanotube 112 by providing charge resulting in an increase in the conductance of the carbon nanotube 112), out through the top metal contact 114A, into the ammeter 422 (to measure the current which has now changed (increase), and back to the voltage source 419. This base is identified according to the measured current, and the voltage source 417 is turned on to move (translocate) the DNA molecule 420 (i.e., break the transient bond), so that the next base can be measured and identified. This process continues until each base has been sequenced.

Now turning to an additional (simultaneous) technique for measuring the change in current to identify respective bases, another ammeter 421 monitors tunneling current between the carbon nanotube 112 and the bottom metal contact 106. In the system 400, a lead (shown with dashed lines) is also connected to the bottom metal contact 106 (e.g., underneath the nanodevice 100). A circuit is formed by the voltage source 419, the top metal contact 114B, the carbon nanotube 112 (the target molecule 420 when present), the buffer solution 450, and the ammeter 421. When the target molecule 420 is not present, the resistance is high because the buffer solution 450 does not contact (i.e., no electrical connection) carbon nanotube 112. Accordingly, the ammeter 421 measures a very small current (and/or no current) which is the baseline current for ammeter 421, when the target molecule 420 is not present and when no DNA base is attached to the carbon nanotube 112.

However, when the 417 drives the DNA molecule 420 into the trench underneath the carbon nanotube 112, the DNA base attaches to the carbon nanotube 112 above. This transient bond allows current (e.g., tunneling current) to flow, and the ammeter 421 measures the current that uniquely corresponds to (identifies) the type of base presently attached to carbon nanotube 112. For each different type of base that is respectively attached to the carbon nanotube 112, the ammeter 421 measures the current that identifies the particular DNA base (and/or RNA base). For example, when a particular DNA base of the DNA molecule 420 is attached (i.e., forms a transient bond to the carbon nanotube 112 above) to the carbon nanotube 112, current flows from the voltage source 419 into the top metal contact 114B, into the carbon nanotube 112, into the attached DNA/RNA base of the target molecule 420 (e.g., as tunneling current), into the buffer solution 450, out through the bottom metal electrode 106, into the ammeter 421 (for

measuring and identifying the attached base), and back to the voltage source 419. The measured current is matched to a predefined current level (for a known base), and the attached based is identified as one of the known bases.

Note that the voltage sources 417 and 419, and the ammeters 418, 421, and 422 may be implemented in a computer system 700 (which may be computer test setup equipment) discussed further below.

FIG. 5 illustrates example view A and view B according to an embodiment. View A illustrates a top view of a scanning electron microscope image of the carbon nanotube 112 suspended over the trench 180 that was masked by top metal contacts 114 (Pd) on either side. Note that the carbon nanotube 112 has been coated with material so that the suspended carbon nanotube 112 is larger and can be more easily viewed in the electron microscope image. Also, the top metal contacts 114 include additional metal patterned on top.

View B illustrates a cross-sectional view of a transmission electron microscope image of a large trench 180 formed in device 100 that was masked by top metal contacts 114 on either side of the trench 180. The carbon nanotube 112 is not visible. Also, this example does not show the <110> crystal orientation for the nonconducting material 110 but shows a different crystal orientation for the nonconducting material 110. As such, the trench 180 has a v shape because of isotropic etching that occurred. Note that the trench 180 has additional metal on top of the embedded bottom metal contact 106.

FIG. 6 illustrates a method of forming device 100 for sequencing according to an embodiment. Reference can be made to FIGS. 1-5 discussed above, along with FIGS. 7 and 8 below.

The bottom metal contact 106 is disposed/embedded at the location 108 in an insulator (e.g., the oxide layer 104) that is on the substrate 102 at block 605.

The nonconducting material 110 is disposed on top of the embedded bottom metal contact 106 and the insulator (oxide layer 104) at block 610.

The carbon nanotube 112 is disposed on top of the nonconducting material 110 at block 615.

At block 620, the top metal contacts 114 are disposed and patterned on top of the carbon nanotube 112 at the location 108 of the bottom metal contact 106, where the top metal contacts 114A and 114B are formed at opposing ends of the carbon nanotube 112 at the location 108 (as shown in FIG. 1C).

At block 625, the carbon nanotube 112 is suspended over the bottom metal contact 106 at the location 108, by etching away the nonconducting material 110 under the carbon nanotube 112 to expose the embedded bottom metal contact 106 as a bottom of a trench 180, while leaving the nonconducting material immediately under the metal contacts as walls of the trench (as shown in FIGS. 1D, 2, and 3).

The carbon nanotube 112 is suspended over the trench 180 without touching the bottom metal contact 106. The top metal contacts 114A and 114B are on opposing sides of the trench 180. The top metal contacts 114A and 114B are electrically connected to one another through the carbon nanotube 112.

As illustrated in FIG. 4, the trench 180 is filled with buffer solution 450 such that the buffer solution 450 does not contact the top metal contacts 114 and does not contact the carbon nanotube 112. In another case, the trench 180 is filled with the buffer solution 450 fully such that the buffer solution 450 does contact (both) the top metal contacts 114 and the carbon nanotube 112.

A thickness of the nonconducting material **110** determines a depth of the trench **180**. A distance separating the top metal contacts **114A** and **114B** determines a width of the trench **180**. A length of the top metal contacts **114A** and **114B** determines the length of the trench **180** (e.g., from front to back).

Additionally, the device **100** can have multiple trenches **180** each having its own corresponding bottom metal contact **106**, where one carbon nanotube **112** is respectively suspended over one of the multiple trenches **180** on a one-to-one basis in order for each carbon nanotube **112** to be individually used to measure the current (as discussed herein) in each respective trench **180**.

FIG. 7 illustrates a method of operating the nanodevice **100** for sequencing the target molecule **420** (such as, e.g., a DNA molecule, RNA molecule, protein, and/or any type of biomolecule having nucleotides (or bases) as understood by one skilled in the art) according to an embodiment. Reference can be made to FIGS. 1-6 discussed above, along with FIGS. 8 below.

At block **705**, voltage (including an electric field) of the voltage source **417** (e.g., which may be implemented in the computer system **700**) translocates the (negatively charged) target molecule **420** through the trench **180** (on the substrate **102**) of the nanodevice **100** in which the nanodevice **100** includes the carbon nanotube **112** suspended over the trench **180** by top metal contacts **114**, and includes the bottom metal contact **106** as the bottom of the trench **180**.

The buffer solution **450** passes both below and above the carbon nanotube **112**, where the carbon nanotube **112** is functionalized with an organic compound having two different functional groups on either end (of the organic compound) in which one functional group attaches to the carbon nanotube **112** and the other functional group interacts with the target molecule **420** (e.g., DNA strand).

A first current flowing between the top metal contacts through the carbon nanotube is measured at block **710**. A change in the first current is measured based on a base of the target molecule **420** in the trench interacting with the carbon nanotube **112** to change a conductance of the carbon nanotube **112** at block **715**. For example, the ammeter **422** (e.g., which may be implemented in the computer system **700**) is configured to measure (first) current flowing between the top metal contacts **114A** and **114B** through the carbon nanotube **112**. The ammeter **422** is configured measure a change in the (first) current based on a base (e.g., DNA/RNA base) of the target molecule **420** in the trench **180** interacting (and attached) with the carbon nanotube **112** to change a conductance (G) of carbon nanotube **112**. The type of base of the target molecule **420** is identified according to the change in current measured (e.g., matched to a known base).

Also, the ammeter **421** (e.g., which may be implemented in the computer system **800**) is configured to measure current flowing between the carbon nanotube **112** and the embedded bottom metal contact **106**, which may be zero or close to zero when no base is attached to the carbon nanotube **112**. The ammeter **421** (e.g., which may be implemented in the computer system **800**) is configured to measure a change in the current based a base of the target molecule **420** in the trench interacting (and attached) with the carbon nanotube **112** to provide an electrical current path (e.g., for tunneling current) between the carbon nanotube **112** and the bottom metal contact **106**. As such, the base of the target molecule **420** is identified according to the change in current measured.

Using the computer **800**, each base may be simultaneously measured by the first current (via ammeter **422**) and

the second current (via ammeter **421**) to identify the base presently attached to the suspended carbon nanotube **112**. Although each of the first current and the second current are capable of identifying the type of base, measuring both bases (simultaneously) provides double verification of for the type of base. The computer **800** can store the time when both the first and second currents are measured for the (same) particular base so that the identified base can be cross checked. Note that voltage of the voltage source **417** may be pulsed to move the target molecule **420** one base at a time through the trench **180** until all of the bases have been sequenced.

FIG. 8 illustrates an example of a computer **800** (e.g., as part of the computer test setup for testing and analysis) which may implement, control, and/or regulate the respective voltages of the voltage sources, respective measurements of the ammeters, and display screens for displaying various current amplitude (including ionic current and transistor (source to drain current)) as discussed herein. The computer **800** also stores the respective electrical current amplitudes of each base tested and measured to be compared against the baselines current amplitudes of different bases, which is utilized to identify the bases of the tested/target molecule.

Various methods, procedures, modules, flow diagrams, tools, applications, circuits, elements, and techniques discussed herein may also incorporate and/or utilize the capabilities of the computer **800**. Moreover, capabilities of the computer **800** may be utilized to implement features of exemplary embodiments discussed herein. One or more of the capabilities of the computer **800** may be utilized to implement, to connect to, and/or to support any element discussed herein (as understood by one skilled in the art) in FIGS. 1-7. For example, the computer **800** which may be any type of computing device and/or test equipment (including ammeters, voltage sources, current meters, connectors, etc.). Input/output device **870** (having proper software and hardware) of computer **800** may include and/or be coupled to the nanodevices and structures discussed herein via cables, plugs, wires, electrodes, patch clamps, etc. Also, the communication interface of the input/output devices **870** comprises hardware and software for communicating with, operatively connecting to, reading, and/or controlling voltage sources, ammeters, and current traces (e.g., magnitude and time duration of current), etc., as discussed and understood herein. The user interfaces of the input/output device **870** may include, e.g., a track ball, mouse, pointing device, keyboard, touch screen, etc., for interacting with the computer **800**, such as inputting information, making selections, independently controlling different voltages sources, and/or displaying, viewing and recording current traces for each base, molecule, biomolecules, etc.

Generally, in terms of hardware architecture, the computer **800** may include one or more processors **810**, computer readable storage memory **820**, and one or more input and/or output (I/O) devices **870** that are communicatively coupled via a local interface (not shown). The local interface can be, for example but not limited to, one or more buses or other wired or wireless connections, as is known in the art. The local interface may have additional elements, such as controllers, buffers (caches), drivers, repeaters, and receivers, to enable communications. Further, the local interface may include address, control, and/or data connections to enable appropriate communications among the aforementioned components.

The processor **810** is a hardware device for executing software that can be stored in the memory **820**. The processor **810** can be virtually any custom made or commercially

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available processor, a central processing unit (CPU), a data signal processor (DSP), or an auxiliary processor among several processors associated with the computer **800**, and the processor **810** may be a semiconductor based microprocessor (in the form of a microchip) or a macroprocessor.

The computer readable memory **820** can include any one or combination of volatile memory elements (e.g., random access memory (RAM), such as dynamic random access memory (DRAM), static random access memory (SRAM), etc.) and nonvolatile memory elements (e.g., ROM, erasable programmable read only memory (EPROM), electronically erasable programmable read only memory (EEPROM), programmable read only memory (PROM), tape, compact disc read only memory (CD-ROM), disk, diskette, cartridge, cassette or the like, etc.). Moreover, the memory **820** may incorporate electronic, magnetic, optical, and/or other types of storage media. Note that the memory **820** can have a distributed architecture, where various components are situated remote from one another, but can be accessed by the processor **810**.

The software in the computer readable memory **820** may include one or more separate programs, each of which comprises an ordered listing of executable instructions for implementing logical functions. The software in the memory **820** includes a suitable operating system (O/S) **850**, compiler **840**, source code **830**, and one or more applications **860** of the exemplary embodiments. As illustrated, the application **860** comprises numerous functional components for implementing the features, processes, methods, functions, and operations of the exemplary embodiments.

The operating system **850** may control the execution of other computer programs, and provides scheduling, input-output control, file and data management, memory management, and communication control and related services.

The application **860** may be a source program, executable program (object code), script, or any other entity comprising a set of instructions to be performed. When a source program, then the program is usually translated via a compiler (such as the compiler **840**), assembler, interpreter, or the like, which may or may not be included within the memory **820**, so as to operate properly in connection with the O/S **850**. Furthermore, the application **860** can be written as (a) an object oriented programming language, which has classes of data and methods, or (b) a procedure programming language, which has routines, subroutines, and/or functions.

The I/O devices **870** may include input devices (or peripherals) such as, for example but not limited to, a mouse, keyboard, scanner, microphone, camera, etc. Furthermore, the I/O devices **870** may also include output devices (or peripherals), for example but not limited to, a printer, display, etc. Finally, the I/O devices **870** may further include devices that communicate both inputs and outputs, for instance but not limited to, a NIC or modulator/demodulator (for accessing remote devices, other files, devices, systems, or a network), a radio frequency (RF) or other transceiver, a telephonic interface, a bridge, a router, etc. The I/O devices **870** also include components for communicating over various networks, such as the Internet or an intranet. The I/O devices **870** may be connected to and/or communicate with the processor **810** utilizing Bluetooth connections and cables (via, e.g., Universal Serial Bus (USB) ports, serial ports, parallel ports, FireWire, HDMI (High-Definition Multimedia Interface), etc.).

In exemplary embodiments, where the application **860** is implemented in hardware, the application **860** can be implemented with any one or a combination of the following technologies, which are each well known in the art: a

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discrete logic circuit(s) having logic gates for implementing logic functions upon data signals, an application specific integrated circuit (ASIC) having appropriate combinational logic gates, a programmable gate array(s) (PGA), a field programmable gate array (FPGA), etc.

As will be appreciated by one skilled in the art, aspects of the present invention may be embodied as a system, method or computer program product. Accordingly, aspects of the present invention may take the form of an entirely hardware embodiment, an entirely software embodiment (including firmware, resident software, micro-code, etc.) or an embodiment combining software and hardware aspects that may all generally be referred to herein as a "circuit," "module" or "system." Furthermore, aspects of the present invention may take the form of a computer program product embodied in one or more computer readable medium(s) having computer readable program code embodied thereon.

Any combination of one or more computer readable medium(s) may be utilized. The computer readable medium may be a computer readable signal medium or a computer readable storage medium. A computer readable storage medium may be, for example, but not limited to, an electronic, magnetic, optical, electromagnetic, infrared, or semiconductor system, apparatus, or device, or any suitable combination of the foregoing. More specific examples (a non-exhaustive list) of the computer readable storage medium would include the following: an electrical connection having one or more wires, a portable computer diskette, a hard disk, a random access memory (RAM), a read-only memory (ROM), an erasable programmable read-only memory (EPROM or Flash memory), an optical fiber, a portable compact disc read-only memory (CD-ROM), an optical storage device, a magnetic storage device, or any suitable combination of the foregoing. In the context of this document, a computer readable storage medium may be any tangible medium that can contain, or store a program for use by or in connection with an instruction execution system, apparatus, or device.

A computer readable signal medium may include a propagated data signal with computer readable program code embodied therein, for example, in baseband or as part of a carrier wave. Such a propagated signal may take any of a variety of forms, including, but not limited to, electromagnetic, optical, or any suitable combination thereof. A computer readable signal medium may be any computer readable medium that is not a computer readable storage medium and that can communicate, propagate, or transport a program for use by or in connection with an instruction execution system, apparatus, or device.

Program code embodied on a computer readable medium may be transmitted using any appropriate medium, including but not limited to wireless, wireline, optical fiber cable, RF, etc., or any suitable combination of the foregoing.

Computer program code for carrying out operations for aspects of the present invention may be written in any combination of one or more programming languages, including an object oriented programming language such as Java, Smalltalk, C++ or the like and conventional procedural programming languages, such as the "C" programming language or similar programming languages. The program code may execute entirely on the user's computer, partly on the user's computer, as a stand-alone software package, partly on the user's computer and partly on a remote computer or entirely on the remote computer or server. In the latter scenario, the remote computer may be connected to the user's computer through any type of network, including a local area network (LAN) or a wide area network (WAN), or

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the connection may be made to an external computer (for example, through the Internet using an Internet Service Provider).

Aspects of the present invention are described below with reference to flowchart illustrations and/or block diagrams of methods, apparatus (systems) and computer program products according to embodiments of the invention. It will be understood that each block of the flowchart illustrations and/or block diagrams, and combinations of blocks in the flowchart illustrations and/or block diagrams, can be implemented by computer program instructions. These computer program instructions may be provided to a processor of a general purpose computer, special purpose computer, or other programmable data processing apparatus to produce a machine, such that the instructions, which execute via the processor of the computer or other programmable data processing apparatus, create means for implementing the functions/acts specified in the flowchart and/or block diagram block or blocks.

These computer program instructions may also be stored in a computer readable medium that can direct a computer, other programmable data processing apparatus, or other devices to function in a particular manner, such that the instructions stored in the computer readable medium produce an article of manufacture including instructions which implement the function/act specified in the flowchart and/or block diagram block or blocks.

The computer program instructions may also be loaded onto a computer, other programmable data processing apparatus, or other devices to cause a series of operational steps to be performed on the computer, other programmable apparatus or other devices to produce a computer implemented process such that the instructions which execute on the computer or other programmable apparatus provide processes for implementing the functions/acts specified in the flowchart and/or block diagram block or blocks.

The flowchart and block diagrams in the Figures illustrate the architecture, functionality, and operation of possible implementations of systems, methods and computer program products according to various embodiments of the present invention. In this regard, each block in the flowchart or block diagrams may represent a module, segment, or portion of code, which comprises one or more executable instructions for implementing the specified logical function (s). It should also be noted that, in some alternative implementations, the functions noted in the block may occur out of the order noted in the figures. For example, two blocks shown in succession may, in fact, be executed substantially concurrently, or the blocks may sometimes be executed in the reverse order, depending upon the functionality involved. It will also be noted that each block of the block diagrams and/or flowchart illustration, and combinations of blocks in the block diagrams and/or flowchart illustration, can be implemented by special purpose hardware-based systems that perform the specified functions or acts, or combinations of special purpose hardware and computer instructions.

The terminology used herein is for the purpose of describing particular embodiments only and is not intended to be limiting of the invention. As used herein, the singular forms "a", "an" and "the" are intended to include the plural forms as well, unless the context clearly indicates otherwise. It will be further understood that the terms "comprises" and/or "comprising," when used in this specification, specify the presence of stated features, integers, steps, operations, elements, and/or components, but do not preclude the presence or addition of one more other features, integers, steps, operations, element components, and/or groups thereof.

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The corresponding structures, materials, acts, and equivalents of all means or step plus function elements in the claims below are intended to include any structure, material, or act for performing the function in combination with other claimed elements as specifically claimed. The description of the present invention has been presented for purposes of illustration and description, but is not intended to be exhaustive or limited to the invention in the form disclosed. Many modifications and variations will be apparent to those of ordinary skill in the art without departing from the scope and spirit of the invention. The embodiment was chosen and described in order to best explain the principles of the invention and the practical application, and to enable others of ordinary skill in the art to understand the invention for various embodiments with various modifications as are suited to the particular use contemplated.

The flow diagrams depicted herein are just one example. There may be many variations to this diagram or the steps (or operations) described therein without departing from the spirit of the invention. For instance, the steps may be performed in a differing order or steps may be added, deleted or modified. All of these variations are considered a part of the claimed invention.

While the preferred embodiment to the invention has been described, it will be understood that those skilled in the art, both now and in the future, may make various improvements and enhancements which fall within the scope of the claims which follow. These claims should be construed to maintain the proper protection for the invention first described.

What is claimed is:

1. A device for sequencing, the device comprising:
 - a bottom metal contact formed at a location in an insulator that is on a substrate;
 - a nonconducting material disposed on top of the bottom metal contact and the insulator;
 - a carbon nanotube disposed on top of the nonconducting material; and
 - top metal contacts disposed on top of the carbon nanotube at the location of the bottom metal contact, wherein the top metal contacts are formed at opposing ends of the carbon nanotube at the location; and
 - wherein the carbon nanotube is suspended over the bottom metal contact at the location, based on etching away the nonconducting material under the carbon nanotube to expose the bottom metal contact as a bottom of a trench, while leaving the nonconducting material immediately under the top metal contacts as walls of the trench.
2. The device of claim 1, wherein the carbon nanotube is suspended over the trench.
3. The device of claim 1, wherein the top metal contacts are on opposing sides of the trench.
4. The device of claim 1, wherein the top metal contacts are electrically connected to one another through the carbon nanotube.
5. The device of claim 1, wherein a thickness of the nonconducting material determines a depth of the trench.
6. The device of claim 1, wherein a distance separating the top metal contacts determines a width of the trench; and wherein a length of the top metal contacts determines a length of the trench.
7. The device of claim 1, further comprising multiple trenches each having its own corresponding bottom metal contact, wherein one carbon nanotube is respectively suspended over one of the multiple trenches on a one-to-one basis.

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